

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/603,937	MIYAGAWA, ICHIROU	
	<b>Examiner</b> Hai C. Pham	<b>Art Unit</b> 2861	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner